Wire-wound Ferrite Power Inductors LBQB/LBQC/LBQE series for Telecommunications Infrastructure and Industrial Equipment Wire-wound Ferrite Power Inductors LBQN/LBQPA series for Telecommunications Infrastructure and Industrial Equipment Wire-wound Ferrite Inductors for Signal Lines LBQM series for Telecommunications Infrastructure and Industrial Equipment Wire-wound Ferrite Power Inductors LMQB/LMQC/LMQE series for Medical Devices classified as GHTF Class C (Japan Class III) Wire-wound Ferrite Power Inductors LMQN/LMQPA series for Medical Devices classified as GHTF Class C (Japan Class III) Wire-wound Ferrite Inductors for Signal Lines LMQM series for Medical Devices classified as GHTF Class C (Japan Class III)

RELIABILITY DATA

1.Operating temper	ature Range
Specified Value	$-40 \sim +105^{\circ} C$ (Including self-generated heat)
Test Methods and Remarks	Including self-generated heat

2. Storage Temperature Range (after soldering)		
Specified Value	-40~+85°C	
Test Methods	Wire-wound Ferrite Inductors, Wire-wound Ferrite Power Inductors:	
and Remarks	Please refer the term of 7. storage conditions in precautions.	

3.Rated Current	
Specified Value	Within the specified tolerance

4.Inductance		
Specified Value	Within the specified tolerance	
Test Methods and Remarks	Measuring equipment :LCR Mater(HP4285A or its equivalent)	
5.Q		
Specified Value	Wire-wound Ferrite Inductors for Signal Lines:	

Test Methods	Wire-wound Ferrite Inductors for Signal Lines :			
and Remarks	Measuring equipment : LCF	R Mater(HP4285A or its equivalent)		
6.DC Resistance				
Specified Value	Within the specified tolerance			

Specified Value	Within the specified tolerance
Test Methods and Remarks	Measuring equipment : DC Ohmmeter (HIOKI 3227 or its equivalent)

7.Self-Resonant Fr	7.Self-Resonant Frequency		
Specified Value	Within the specified tolerance		
Test Methods and Remarks	Measuring equipment : Impedance analyzer (HP4291A or its equivalent)		

8.Temperature Characteristic							
	LBQMB2016					t I . I Well' I 1007	
	LMQMB20	016				Inductance change : Within ± 10%	
	LBQBA20	12 LBQEA2012	LBQNA2012	LBQBA	2016		
	LBQNA20	16 LBQBA2518	LBQEA2518	LBQNA	2518		
	LBQCA32	25 LBQPA3225				Industance change Within + 2004	
	LMQBA20	12 LMQEA2012	LMQNA2012	LMQBA	2016	Inductance change : Within 120%	
Cara different Markers	LMQNA20	16 LMQBA2518	LMQEA2518	LMQNA	2518		
Specified Value	LMQCA32	25 LMQPA3225					
	LBQCA20	16 LBQPA2016	LBQCA2518	LBQPA	2518		
	LBQBA3218						
	LMQCA20	016 LMQPA2016	LMQCA2518	LMQPA	2518	Inductance change : Within 123%	
	LMQBA3218						
	LBQCA20	12 LBQPA2012				Industance shares Within + 2504	
	LMQCA20	012 LMQPA2012				Inductance change : Within 135%	
	Change of maximum inductance deviation in step 1-5						
	Step	Temperature (°C)					
Test Methods	1	20					
and Remarks	2	-40					
	3	20(Reference temperature)					
	4	+85(Maximum operating temperature)					
	5	20					

9.Rasistance to Flexure of Substrate Specified Value No damage. Warp : 2mm Test substrate : Board according to JIS C0051 Thickness : 1.0mm Pressing jig

Test Methods and Remarks

10.Body Strength		
Specified Value	No damage.	
Test Methods and Remarks	Applied force Duration	: 10N : 10sec.

11.Adhesion of term	ninal electrode	
Specified Value	No abnormality.	
Test Methods and Remarks	Applied force Duration Test substrate	: 10N to X and Y directions 5 sec. : Printed board

12.Resistance to vi	bration			
Specified Value	Inductance change : Within±20% No significant abnormality in appearance.			
Test Methods and Remarks	According to JIS C510 Vibration type Directions Frequency range Amplitude Mounting method Recovery	 2 clause 8.2. : A : 2 hrs each in X, Y and Z directions. Total: 6 hrs : 10 to 55 to 10 Hz(1min.) : 1.5mm : Soldering onto printed board : At least 2 hrs of recovery under the standard condition after the test, followed by the measurement within 48 hrs. 		

13.Drop test	
Specified Value	—

14.Solderability		
Specified Value	At least 90% of surface of terminal electrode is covered by new	
Test Methods and Remarks	Solder temperature Duration Flux	: 245±5°C : 5±0.5sec : Ethanol solution with 25% of colophony

15.Resistance to soldering		
Specified Value	Inductance change : Within±20%	
Test Methods and Remarks	3 times of reflow oven at 230°C MIN for 40sec. with peak temperature at 260 $$ °C for 5sec.	

16.Resisitance to solvent		
Specified Value	-	
Test Methods and Remarks	Solvent temperature Type of solvent Cleaning conditions	: Room temperature : Isopropyl alcohol : 90s. Immersion and cleaning.

17.Thermal shock			
Specified Value	Inductance change : Within±20%		
	No significant abnormality in appearance.		
Test Methods	-40 \sim $+85^{\circ}$ C, maintain times 30min. ,100 cycle		
and Remarks	Recovery : At least 2 hrs of recovery under the standard condition after the test, followed by the measurement within 48 hrs	s.	

18.Damp heat life test		
Specified Value	Inductance change : Within±20% No significant abnormality in appearance.	
Test Methods and Remarks	Temperature Humidity Duration Recovery	: 60±2°C : 90~95%RH : 1000 hrs : At least 2 hrs of recovery under the standard condition after the test, followed by the measurement within 48 hrs.

19.Loading under damp heat life test			
Specified Value	Inductance change : Within±20% No significant abnormality in appearance.		
Test Methods and Remarks	Temperature Humidity Duration Applied current Recovery	: 60±2°C : 90~95%RH : 1000 hrs : Rated current : At least 2 hrs of recovery under the standard condition after the test, followed by the measurement within 48 hrs.	

20.High temperature life test		
Specified Value	Wire-wound Ferrite Power Inductors, Wire-wound Ferrite Inductors for Signal Lines : Inductance change : Within土20% No significant abnormality in appearance	
Test Methods and Remarks	Temperature Duration Recovery	: 85±2°C : 1000 hrs : At least 2 hrs of recovery under the standard condition after the test, followed by the measurement within 48 hrs.

21.Loading at high temperature life test		
Specified Value	Wire-wound Ferrite Inductors: Inductance change : Within±20% No significant abnormality in appearance	
Test Methods and Remarks	Temperature Duration Applied current Recovery	: 85±2°C : 1000 hrs : Rated current : At least 2 hrs of recovery under the standard condition after the test, followed by the measurement within 48 hrs.

22.Low temperature	e life test	
Specified Value	Inductance change : Within±20% No significant abnormality in appearance.	
Test Methods and Remarks	Temperature Duration Recovery	: −40±2°C : 1000 hrs : At least 2 hrs of recovery under the standard condition after the test, followed by the measurement within 48 hrs.

23.Standard condition		
Specified Value	Standard test conditions Unless specified, Ambient temperature is $20\pm15^{\circ}$ C and the Relative humidity is $65\pm20\%$. If there is any doubt about the test results, further measurement shall be had within the following limits: Ambient Temperature: $20\pm2^{\circ}$ C Relative humidity: $65\pm5\%$ Inductance value is based on our standard measurement systems.	



LBQB/LBQC/LBQE series

Derating of current is necessary for LBQB/LBQC/LBQE series series depending on ambient temperature. Please refer to the chart shown below for appropriate derating of current.





LBQN/LBQPA series

Derating of current is necessary for LBQN/LBQPA series depending on ambient temperature. Please refer to the chart shown below for appropriate derating of current.





LBQM series

Derating of current is necessary for LBQM series depending on ambient temperature. Please refer to the chart shown below for appropriate derating of current.



LMQB/LMQC/LMQE series

Derating of current is necessary for LMQB/LMQC/LMQE series series depending on ambient temperature. Please refer to the chart shown below for appropriate derating of current.





LMQN/LMQPA series

Derating of current is necessary for LMQN/LMQPA series depending on ambient temperature. Please refer to the chart shown below for appropriate derating of current.





LMQM series

Derating of current is necessary for LMQM series depending on ambient temperature. Please refer to the chart shown below for appropriate derating of current.

